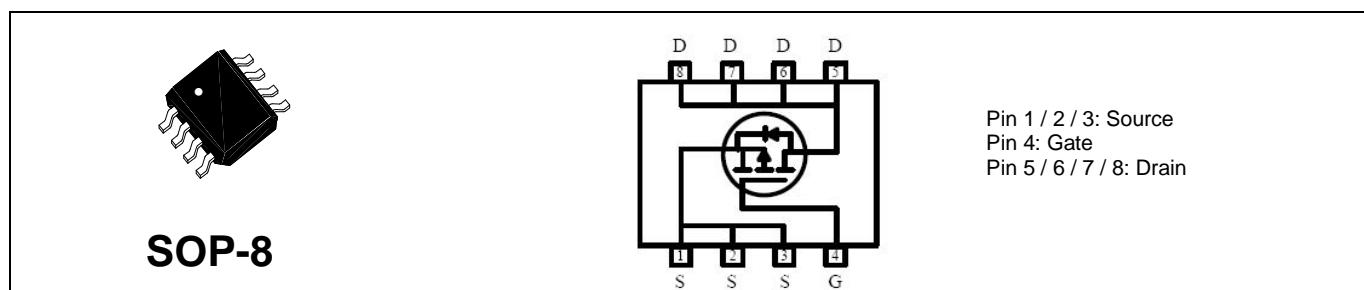


**P-Channel Enhancement-Mode MOSFET (-30V, -12A)**

PRODUCT SUMMARY		
V _{DSS}	I _D	R _{D(on)} (m-ohm) Max
-30V	-12A	13 @ V _{GS} = -20V ,ID=-10A
		20 @ V _{GS} = -10V ,ID=-10A
		28 @ V _{GS} = -5V ,ID=-10A

Features

- Advanced Trench Process Technology
- High Density Cell Design for Ultra Low On-Resistance
- Lead free product is acquired

**Absolute Maximum Ratings** ($T_A=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Ratings	Units
V _{DS}	Drain-Source Voltage	-30	V
V _{GS}	Gate-Source Voltage	± 20	V
I _D	Drain Current @ $T_A=25^\circ\text{C}$	-10	A
I _{DM}	Drain Current (Pulsed) ^a	-60	A
I _{AR}	Avalanche Current	30	A
E _{AR}	Repetitive Avalanche Energy L=0.3mH	135	mJ
P _D	Total Power Dissipation @ $T_A=25^\circ\text{C}$	3	W
	Total Power Dissipation @ $T_A=75^\circ\text{C}$	2.1	
I _S	Maximum Diode Forward Current	-2.1	A
T _j , T _{stg}	Operating Junction and Storage Temperature Range	-55 to +150	°C
R _{θJA}	Thermal Resistance Junction to Ambient (PCB mounted) ^b	50	°C/W

a: Repetitive Rating: Pulse width limited by the maximum junction temperature.

b: 1-in² 2oz Cu PCB board

**Electrical Characteristics** ($T_A=25^\circ\text{C}$, unless otherwise noted)

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
• Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=-24\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{\text{GS}}=\pm 25\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
• On Characteristics^c						
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-1.0	-	-3.0	V
$I_{\text{DS}(\text{on})}$	On State Drain Current	$V_{\text{DS}}=-5\text{V}, V_{\text{GS}}=-10\text{V}$	60	-	-	A
$R_{\text{DS}(\text{on})}$	Drain-Source On-State Resistance					$\text{m}\Omega$
		$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-10\text{A}$	-	-	14	
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-6\text{A}$	-	-	20	
g_{FS}	Forward Transconductance	$V_{\text{DS}}=-10\text{V}, I_{\text{D}}=-5\text{A}$	-	26	-	S
• Dynamic Characteristics^d						
C_{iss}	Input Capacitance	$V_{\text{DS}}=-15\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	2076	2500	pF
C_{oss}	Output Capacitance		-	503	-	
C_{rss}	Reverse Transfer Capacitance		-	302	423	
R_g	Gate Resistance	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	1	2	3	Ω
• Switching Characteristics^d						
Q_g	Total Gate Charge	$V_{\text{DS}}=-15\text{V}, I_{\text{D}}=-12\text{A}, V_{\text{GS}}=-10\text{V}$	-	37.2	-	nC
Q_{gs}	Gate-Source Charge		-	7	-	
Q_{gd}	Gate-Drain Charge		-	10.4	-	
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DD}}=-15\text{V}, R_L=1.25\Omega, V_{\text{GS}}=-10\text{V}, R_G=3\Omega$	-	12.4	-	nS
t_r	Turn-on Rise Time		-	8.2	-	
$t_{\text{d}(\text{off})}$	Turn-off Delay Time		-	25.6	-	
t_f	Turn-off Fall Time		-	12	-	
t_{rr}	Reverse Recovery Time	$I_{\text{DS}}=-12\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	33	40	nS
Q_{rr}	Reverse Recovery Charge		-	23	-	nC
• Drain-Source Diode Characteristics						
V_{SD}	Drain-Source Diode Forward Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{S}}=-1\text{A}$	-	-	-1	V
I_{S}	Drain-Source Diode Forward Current		-	-	-4.2	A

Note: Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$



Characteristics Curve

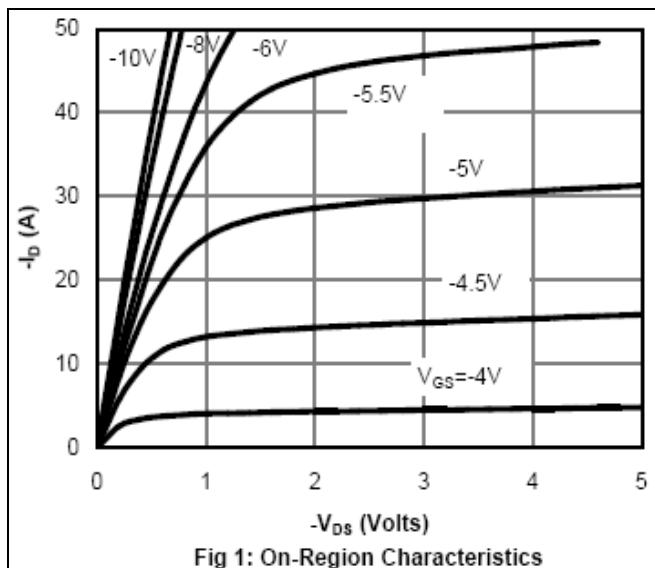


Fig 1: On-Region Characteristics

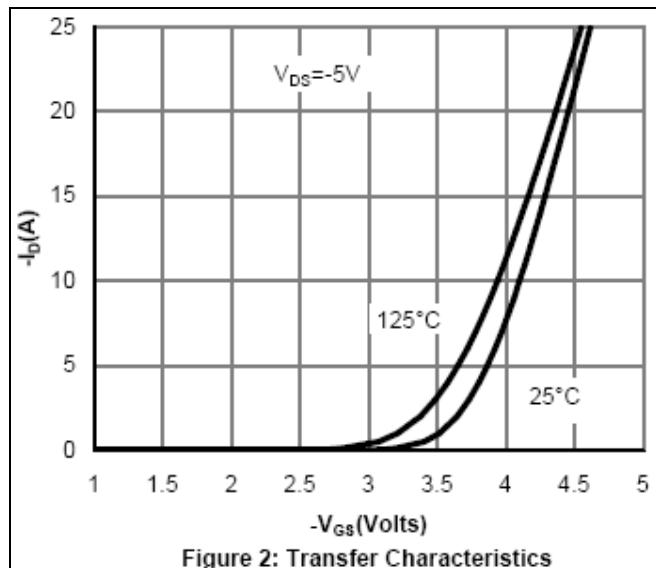


Figure 2: Transfer Characteristics

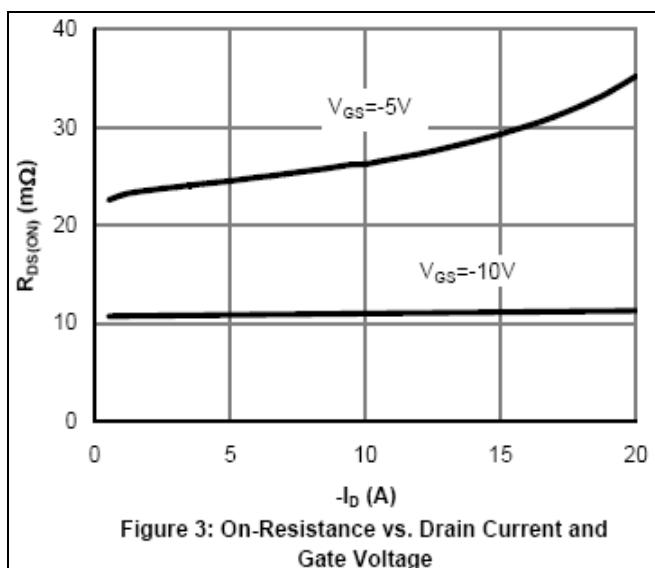


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

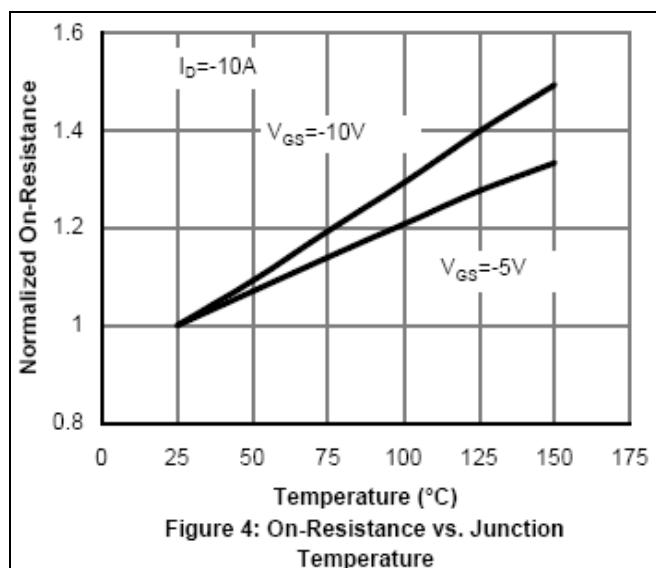


Figure 4: On-Resistance vs. Junction Temperature

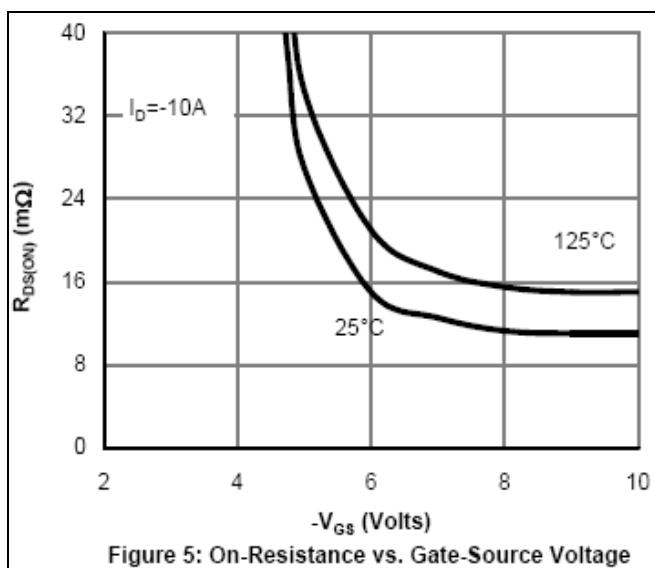


Figure 5: On-Resistance vs. Gate-Source Voltage

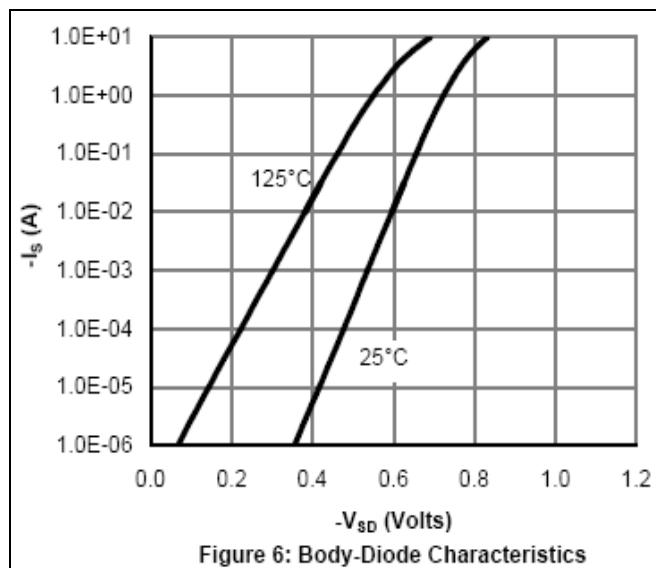


Figure 6: Body-Diode Characteristics



Characteristics Curve

